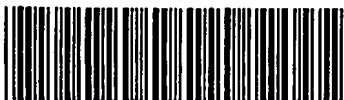


Search Notes



Application/Control No.

10/500,572

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

SHIMADA, AKIHIRO

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	52	10/19/2006	HN
310	54	10/19/2006	HN
310	58	10/19/2006	HN
310	64	10/19/2006	HN
310	90	10/19/2006	HN
310	90.5	10/19/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consult Dang Le, Primary Examiner for Allowance	10/19/06	HN